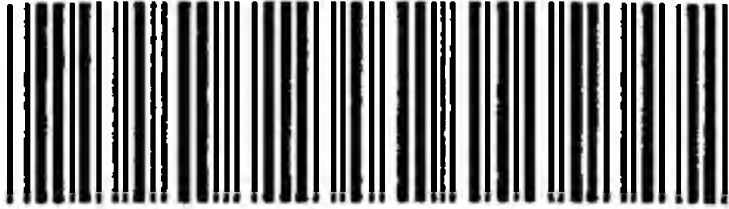


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,421	SHEI ET AL.	
	Examiner	Art Unit	
	Joseph Nguyen	2815	

SEARCHED			
Class	Subclass	Date	Examiner
257	99,79	7/26/2005	JN
257	90	7/26/2005	JN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search history printout	7/26/2005	JN